| | Amplication No. | [A = 1! 4/-) |
|---|---|---|
| Notice of Allowability | Application No. | Applicant(s) |
| | 10/644,415 | KITO ET AL. |
| | Examiner | Art Unit |
| | Tu-Tu Ho | 2818 |
| The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313 | i (OR REMAINS) CLOSED in this ap) or other appropriate communicatio B GHTS. This application is subject t | oplication. If not included n will be mailed in due course. THIS |
| 1. This communication is responsive to Paper filed 08/26/200 | <u>04</u> . | |
| 2. The allowed claim(s) is/are <u>1-6</u> . | | |
| 3. \boxtimes The drawings filed on <u>20 August 2003</u> are accepted by the | e Examiner. | |
| 4. Acknowledgment is made of a claim for foreign priority u a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: | e been received. e been received in Application No | |
| Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. | | complying with the requirements |
| 5. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which giv | | |
| CORRECTED DRAWINGS (as "replacement sheets") mu (a) ☐ including changes required by the Notice of Draftsper 1) ☐ hereto or 2) ☐ to Paper No./Mail Date (b) ☐ including changes required by the attached Examiner Paper No./Mail Date | son's Patent Drawing Review(PTO - | , |
| Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in | | |
| 7. DEPOSIT OF and/or INFORMATION about the deposit attached Examiner's comment regarding REQUIREMENT | | |
| Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948) 3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/Paper No./Mail Date 08/20/2003 4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material | 6. ☐ Interview Summary Paper No./Mail Da 08), 7. ☒ Examiner's Amend | ate |
| | David Nelms Supervisory Patent Examiner Technology Center 2800 | |

DETAILED ACTION

Priority

1. Receipt is acknowledged of papers submitted under 35 U.S.C. 119(a)-(d), which papers have been placed of record in the file.

Examiner's Amendment

- 2. An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.
- 3. This application is in condition for allowance except for the presence of claims 7-14 non-elected without traverse. Accordingly, claims 7-14 have been cancelled.

Allowable Subject Matter

4. Claims 1-6 are allowable over the prior art of record.

The following is an examiner's statement of reasons for allowance: The prior art of record fails to teach or render obvious a semiconductor device including memory cells each having a trench capacitor and a fin-gate-type MOSFET (FinFET) for selecting the trench capacitor with all limitations as recited in claim 1, comprising a pillar on a surface of a semiconductor substrate, a gate electrode functioning as a word line (WL), a first active region in the pillar and connected

to a bit line (BL), a second active region in the pillar, the trench capacitor formed adjacent the second active region, a device isolation region, an oxide film on the device isolation region, and a conductive surface strap on the oxide film for connecting the second active region and an electrode of the trench capacitor, the gate electrode being formed on a side wall and on an upper surface of the pillar, the oxide film being located lower than the upper surface of the pillar, and contact between the conductive surface strap and the second active region being made at the upper surface and at the side wall of the pillar.

Page 3

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

- 5. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. Copies of the references are not being furnished with this Office Action per MPEP § 707.05(a).
- a) U.S. Patent 6,664,582 to Fried et al. discloses and claims a FinFET and a fin capacitor using the same fin.
- b) U.S. Patent Application Publication 2002/0011612 by Hieda discloses and is claiming a semiconductor transistor having a convex semiconductor layer.

Application/Control Number: 10/644,415 Page 4

Art Unit: 2818

6. Any inquiry concerning this communication or earlier communications from the examiner should be directed to Tu-Tu Ho whose telephone number is (571) 272-1778. The examiner can normally be reached on 6:30 am - 5:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, DAVID NELMS can be reached on (571) 272-1787. The fax phone number for the organization where this application or proceeding is assigned is (703) 872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Tu-Tu Ho

September 21, 2004

David Nelms
Supervisory Patent Examiner
Technology Center 2800